Infeon Technologies - XC2785X104F80LRABKXUMA1 Datasheet

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"Embedded - Microcontrollers" refer to small, integrated circuits designed to perform specific tasks within larger systems. These microcontrollers are essentially compact computers on a single chip, containing a processor core, memory, and programmable input/output peripherals. They are called "embedded" because they are embedded within electronic devices to control various functions, rather than serving as standalone computers. Microcontrollers are crucial in modern electronics, providing the intelligence and control needed for a wide range of applications.

Applications of "Embedded - Microcontrollers"

Details	
Product Status	Not For New Designs
Core Processor	C166SV2
Core Size	16/32-Bit
Speed	80MHz
Connectivity	CANbus, EBI/EMI, I²C, LINbus, SPI, SSC, UART/USART, USI
Peripherals	I²S, POR, PWM, WDT
Number of I/O	116
Program Memory Size	832KB (832K x 8)
Program Memory Type	FLASH
EEPROM Size	-
RAM Size	50K x 8
Voltage - Supply (Vcc/Vdd)	3V ~ 5.5V
Data Converters	A/D 24x10b
Oscillator Type	Internal
Operating Temperature	-40°C ~ 125°C (TA)
Mounting Type	Surface Mount
Package / Case	144-LQFP Exposed Pad
Supplier Device Package	PG-LQFP-144-4
Purchase URL	https://www.e-xfl.com/product-detail/infineon-technologies/xc2785x104f80lrabkxuma1

  - Two Synchronizable A/D Converters with a total of up to 24 channels, 10-bit resolution, conversion time below 1 µs, optional data preprocessing (data reduction, range check), broken wire detection
  - Up to 6 serial interface channels to be used as UART, LIN, high-speed synchronous channel (SPI), IIC bus interface (10-bit addressing, 400 kbit/s), IIS interface
  - On-chip MultiCAN interface (Rev. 2.0B active) with up to 64 message objects (Full CAN/Basic CAN) on up to 2 CAN nodes and gateway functionality
  - On-chip system timer and on-chip real time clock
- Up to 12 Mbytes external address space for code and data
  - Programmable external bus characteristics for different address ranges
  - Multiplexed or demultiplexed external address/data buses
  - Selectable address bus width
  - 16-bit or 8-bit data bus width
  - Five programmable chip-select signals
  - Hold- and hold-acknowledge bus arbitration support
- Single power supply from 3.0 V to 5.5 V
- Programmable watchdog timer and oscillator watchdog
- Up to 119 general purpose I/O lines
- On-chip bootstrap loaders
- Supported by a full range of development tools including C compilers, macro-assembler packages, emulators, evaluation boards, HLL debuggers, simulators, logic analyzer disassemblers, programming boards
- On-chip debug support via Device Access Port (DAP) or JTAG interface
- 144-pin Green LQFP package, 0.5 mm (19.7 mil) pitch

2.1 Pin Configuration and Definition

The pins of the XC2785X are described in detail in **Table 6**, which includes all alternate functions. For further explanations please refer to the footnotes at the end of the table. The following figure summarizes all pins, showing their locations on the four sides of the package.

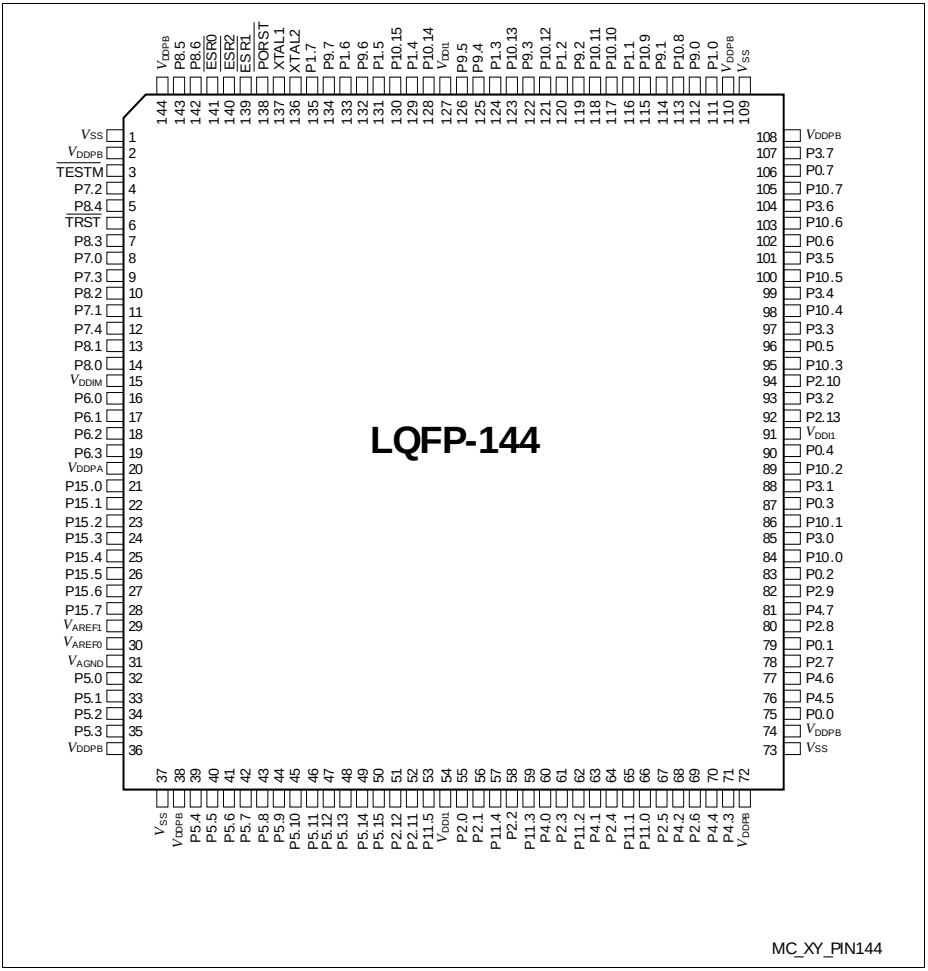

Figure 3 XC2785X Pin Configuration (top view)

Table 6 Pin Definitions and Functions (cont'd)

Pin	Symbol	Ctrl.	Type	Function
82	P2.9	O0 / I	St/B	**Bit 9 of Port 2, General Purpose Input/Output**
	U0C1_DOUT	O1	St/B	**USIC0 Channel 1 Shift Data Output**
	TxDC1	O2	St/B	**CAN Node 1 Transmit Data Output**
	CC2_CC22	O3 / I	St/B	**CAPCOM2 CC22IO Capture Inp./ Compare Out.**
	A22	OH	St/B	**External Bus Interface Address Line 22**
	CLKIN1	I	St/B	**Clock Signal Input 1**
	TCK_A	IH	St/B	**DAP0/JTAG Clock Input** If JTAG pos. A is selected during start-up, an internal pull-up device will hold this pin high when nothing is driving it. If DAP pos. 0 is selected during start-up, an internal pull-down device will hold this pin low when nothing is driving it.
83	P0.2	O0 / I	St/B	**Bit 2 of Port 0, General Purpose Input/Output**
	U1C0_SCLKOUT	O1	St/B	**USIC1 Channel 0 Shift Clock Output**
	TxDC0	O2	St/B	**CAN Node 0 Transmit Data Output**
	CCU61_CC62	O3	St/B	**CCU61 Channel 2 Output**
	A2	OH	St/B	**External Bus Interface Address Line 2**
	U1C0_DX1B	I	St/B	**USIC1 Channel 0 Shift Clock Input**
	CCU61_CC62INA	I	St/B	**CCU61 Channel 2 Input**

Table 6 Pin Definitions and Functions (cont'd)

Pin	Symbol	Ctrl.	Type	Function
99	P3.4	O0 / I	St/B	**Bit 4 of Port 3, General Purpose Input/Output**
	U2C1_SELO 0	O1	St/B	**USIC2 Channel 1 Select/Control 0 Output**
	U2C0_SELO 1	O2	St/B	**USIC2 Channel 0 Select/Control 1 Output**
	U0C0_SELO 4	O3	St/B	**USIC0 Channel 0 Select/Control 4 Output**
	U2C1_DX2A	I	St/B	**USIC2 Channel 1 Shift Control Input**
100	P10.5	O0 / I	St/B	**Bit 5 of Port 10, General Purpose Input/Output**
	U0C1_SCLK OUT	O1	St/B	**USIC0 Channel 1 Shift Clock Output**
	CCU60_COU T62	O2	St/B	**CCU60 Channel 2 Output**
	U2C0_DOUT	O3	St/B	**USIC2 Channel 0 Shift Data Output**
	AD5	OH / IH	St/B	**External Bus Interface Address/Data Line 5**
	U0C1_DX1B	I	St/B	**USIC0 Channel 1 Shift Clock Input**
101	P3.5	O0 / I	St/B	**Bit 5 of Port 3, General Purpose Input/Output**
	U2C1_SCLK OUT	O1	St/B	**USIC2 Channel 1 Shift Clock Output**
	U2C0_SELO 2	O2	St/B	**USIC2 Channel 0 Select/Control 2 Output**
	U0C0_SELO 5	O3	St/B	**USIC0 Channel 0 Select/Control 5 Output**
	U2C1_DX1A	I	St/B	**USIC2 Channel 1 Shift Clock Input**

Table 6 Pin Definitions and Functions (cont'd)

Pin	Symbol	Ctrl.	Type	Function
105	P10.7	O0 / I	St/B	**Bit 7 of Port 10, General Purpose Input/Output**
	U0C1_DOUT	O1	St/B	**USIC0 Channel 1 Shift Data Output**
	CCU60_COUT63	O2	St/B	**CCU60 Channel 3 Output**
	AD7	OH / IH	St/B	**External Bus Interface Address/Data Line 7**
	U0C1_DX0B	I	St/B	**USIC0 Channel 1 Shift Data Input**
	CCU60_CCPOS0A	I	St/B	**CCU60 Position Input 0**
	T4INB	I	St/B	**GPT12E Timer T4 Count/Gate Input**
106	P0.7	O0 / I	St/B	**Bit 7 of Port 0, General Purpose Input/Output**
	U1C1_DOUT	O1	St/B	**USIC1 Channel 1 Shift Data Output**
	U1C0_SELO3	O2	St/B	**USIC1 Channel 0 Select/Control 3 Output**
	A7	OH	St/B	**External Bus Interface Address Line 7**
	U1C1_DX0B	I	St/B	**USIC1 Channel 1 Shift Data Input**
	CCU61_CTRAPB	I	St/B	**CCU61 Emergency Trap Input**
107	P3.7	O0 / I	St/B	**Bit 7 of Port 3, General Purpose Input/Output**
	U2C1_DOUT	O1	St/B	**USIC2 Channel 1 Shift Data Output**
	U2C0_SELO3	O2	St/B	**USIC2 Channel 0 Select/Control 3 Output**
	U0C0_SELO7	O3	St/B	**USIC0 Channel 0 Select/Control 7 Output**
	U2C1_DX0B	I	St/B	**USIC2 Channel 1 Shift Data Input**

Table 6 Pin Definitions and Functions (cont'd)

Pin	Symbol	Ctrl.	Type	Function
120	P1.2	O0 / I	St/B	**Bit 2 of Port 1, General Purpose Input/Output**
	CCU62_CC62	O1	St/B	**CCU62 Channel 2 Output**
	U1C0_SELO6	O2	St/B	**USIC1 Channel 0 Select/Control 6 Output**
	U2C1_SCLKOUT	O3	St/B	**USIC2 Channel 1 Shift Clock Output**
	A10	OH	St/B	**External Bus Interface Address Line 10**
	ESR1_4	I	St/B	**ESR1 Trigger Input 4**
	CCU61_T12HRB	I	St/B	**External Run Control Input for T12 of CCU61**
	CCU62_CC62INA	I	St/B	**CCU62 Channel 2 Input**
	U2C1_DX0D	I	St/B	**USIC2 Channel 1 Shift Data Input**
	U2C1_DX1C	I	St/B	**USIC2 Channel 1 Shift Clock Input**
121	P10.12	O0 / I	St/B	**Bit 12 of Port 10, General Purpose Input/Output**
	U1C0_DOUT	O1	St/B	**USIC1 Channel 0 Shift Data Output**
	TDO_B	OH / IH	St/B	**JTAG Test Data Output / DAP1 Input/Output** If DAP pos. 1 is selected during start-up, an internal pull-down device will hold this pin low when nothing is driving it.
	AD12	OH / IH	St/B	**External Bus Interface Address/Data Line 12**
	U1C0_DX0C	I	St/B	**USIC1 Channel 0 Shift Data Input**
	U1C0_DX1E	I	St/B	**USIC1 Channel 0 Shift Clock Input**
122	P9.3	O0 / I	St/B	**Bit 3 of Port 9, General Purpose Input/Output**
	CCU63_COUT60	O1	St/B	**CCU63 Channel 0 Output**
	$\overline{\text{BRKOUT}}$	O2	St/B	**OCDS Break Signal Output**

Table 6 Pin Definitions and Functions (cont'd)

Pin	Symbol	Ctrl.	Type	Function
134	P9.7	O0 / I	St/B	**Bit 7 of Port 9, General Purpose Input/Output**
	CCU62_COUT60	O1	St/B	**CCU62 Channel 0 Output**
	CCU62_COUT63	O2	St/B	**CCU62 Channel 3 Output**
	CCU63_CTRAPB	I	St/B	**CCU63 Emergency Trap Input**
	U2C0_DX1D	I	St/B	**USIC2 Channel 0 Shift Clock Input**
	CCU60_CCPOS0B	I	St/B	**CCU60 Position Input 0**
135	P1.7	O0 / I	St/B	**Bit 7 of Port 1, General Purpose Input/Output**
	CCU62_CC60	O1	St/B	**CCU62 Channel 0 Output**
	U1C1_MCLKOUT	O2	St/B	**USIC1 Channel 1 Master Clock Output**
	U2C0_SCLKOUT	O3	St/B	**USIC2 Channel 0 Shift Clock Output**
	A15	OH	St/B	**External Bus Interface Address Line 15**
	U2C0_DX1C	I	St/B	**USIC2 Channel 0 Shift Clock Input**
	CCU62_CC60INA	I	St/B	**CCU62 Channel 0 Input**
136	XTAL2	O	Sp/M	**Crystal Oscillator Amplifier Output**
137	XTAL1	I	Sp/M	**Crystal Oscillator Amplifier Input** To clock the device from an external source, drive XTAL1, while leaving XTAL2 unconnected. Voltages on XTAL1 must comply to the core supply voltage V_{DDIM}.
	ESR2_9	I	St/B	**ESR2 Trigger Input 9**

3.2 External Bus Controller

All external memory access operations are performed by a special on-chip External Bus Controller (EBC). The EBC also controls access to resources connected to the on-chip LXBus (MultiCAN and the USIC modules). The LXBus is an internal representation of the external bus that allows access to integrated peripherals and modules in the same way as to external components.

The EBC can be programmed either to Single Chip Mode, when no external memory is required, or to an external bus mode with the following selections[1]:

- Address Bus Width with a range of 0 … 24-bit
- Data Bus Width 8-bit or 16-bit
- Bus Operation Multiplexed or Demultiplexed

The bus interface uses Port 10 and Port 2 for addresses and data. In the demultiplexed bus modes, the lower addresses are output separately on Port 0 and Port 1. The number of active segment address lines is selectable, restricting the external address space to 8 Mbytes … 64 Kbytes. This is required when interface lines shall be assigned to Port 2.

External $\overline{CS}$ signals (address windows plus default) can be generated and output on Port 4 in order to save external glue logic. External modules can be directly connected to the common address/data bus and their individual select lines.

A $\overline{HOLD}$/$\overline{HLDA}$ protocol is available for bus arbitration; this allows the sharing of external resources with other bus masters. The bus arbitration is enabled by software, after which pins P3.0 … P3.2 ($\overline{BREQ}$, $\overline{HLDA}$, $\overline{HOLD}$) are automatically controlled by the EBC. In Master Mode (default after reset) the $\overline{HLDA}$ pin is an output. In Slave Mode pin $\overline{HLDA}$ is switched to be an input. This allows the direct connection of the slave controller to another master controller without glue logic.

Important timing characteristics of the external bus interface are programmable (with registers TCONCSx/FCONCSx) to allow the user to adapt it to a wide range of different types of memories and external peripherals.
Access to very slow memories or modules with varying access times is supported by a special ‘Ready’ function. The active level of the control input signal is selectable.

In addition, up to four independent address windows may be defined (using registers ADDRSELx) to control access to resources with different bus characteristics. These address windows are arranged hierarchically where window 4 overrides window 3, and window 2 overrides window 1. All accesses to locations not covered by these four address windows are controlled by TCONCS0/FCONCS0. The currently active window can generate a chip select signal.

The external bus timing is based on the rising edge of the reference clock output CLKOUT. The external bus protocol is compatible with that of the standard C166 Family.

1) Bus modes are switched dynamically if several address windows with different mode settings are used.

to a dedicated vector table location). The occurrence of a hardware trap is also indicated by a single bit in the trap flag register (TFR). Unless another higher-priority trap service is in progress, a hardware trap will interrupt any ongoing program execution. In turn, hardware trap services can normally not be interrupted by standard or PEC interrupts.

Depending on the package option up to 3 External Service Request (ESR) pins are provided. The ESR unit processes their input values and allows to implement user controlled trap functions (System Requests SR0 and SR1). In this way reset, wakeup and power control can be efficiently realized.

Software interrupts are supported by the 'TRAP' instruction in combination with an individual trap (interrupt) number. Alternatively to emulate an interrupt by software a program can trigger interrupt requests by writing the Interrupt Request (IR) bit of an interrupt control register.

3.7 On-Chip Debug Support (OCDS)

The On-Chip Debug Support system built into the XC2785X provides a broad range of debug and emulation features. User software running on the XC2785X can be debugged within the target system environment.

The OCDS is controlled by an external debugging device via the debug interface. This either consists of the 2-pin Device Access Port (DAP) or of the JTAG port conforming to IEEE-1149. The debug interface can be completed with an optional break interface.

The debugger controls the OCDS with a set of dedicated registers accessible via the debug interface (DAP or JTAG). In addition the OCDS system can be controlled by the CPU, e.g. by a monitor program. An injection interface allows the execution of OCDS-generated instructions by the CPU.

Multiple breakpoints can be triggered by on-chip hardware, by software, or by an external trigger input. Single stepping is supported, as is the injection of arbitrary instructions and read/write access to the complete internal address space. A breakpoint trigger can be answered with a CPU halt, a monitor call, a data transfer, or/and the activation of an external signal.

Tracing data can be obtained via the debug interface, or via the external bus interface for increased performance.

Tracing of program execution is supported by the XC2000 Family emulation device.

The DAP interface uses two interface signals, the JTAG interface uses four interface signals, to communicate with external circuitry. The debug interface can be amended with two optional break lines.

3.19 Instruction Set Summary

Table 11 lists the instructions of the XC2785X.
The addressing modes that can be used with a specific instruction, the function of the instructions, parameters for conditional execution of instructions, and the opcodes for each instruction can be found in the **“Instruction Set Manual”**.

This document also provides a detailed description of each instruction.

Table 11 Instruction Set Summary

Mnemonic	Description	Bytes
ADD(B)	Add word (byte) operands	2 / 4
ADDC(B)	Add word (byte) operands with Carry	2 / 4
SUB(B)	Subtract word (byte) operands	2 / 4
SUBC(B)	Subtract word (byte) operands with Carry	2 / 4
MUL(U)	(Un)Signed multiply direct GPR by direct GPR (16- × 16-bit)	2
DIV(U)	(Un)Signed divide register MDL by direct GPR (16-/16-bit)	2
DIVL(U)	(Un)Signed long divide reg. MD by direct GPR (32-/16-bit)	2
CPL(B)	Complement direct word (byte) GPR	2
NEG(B)	Negate direct word (byte) GPR	2
AND(B)	Bitwise AND, (word/byte operands)	2 / 4
OR(B)	Bitwise OR, (word/byte operands)	2 / 4
XOR(B)	Bitwise exclusive OR, (word/byte operands)	2 / 4
BCLR/BSET	Clear/Set direct bit	2
BMOV(N)	Move (negated) direct bit to direct bit	4
BAND/BOR/BXOR	AND/OR/XOR direct bit with direct bit	4
BCMP	Compare direct bit to direct bit	4
BFLDH/BFLDL	Bitwise modify masked high/low byte of bit-addressable direct word memory with immediate data	4
CMP(B)	Compare word (byte) operands	2 / 4
CMPD1/2	Compare word data to GPR and decrement GPR by 1/2	2 / 4
CMPI1/2	Compare word data to GPR and increment GPR by 1/2	2 / 4
PRIOR	Determine number of shift cycles to normalize direct word GPR and store result in direct word GPR	2
SHL/SHR	Shift left/right direct word GPR	2

4.2.1 DC Parameters

Keeping signal levels within the limits specified in this table ensures operation without overload conditions. For signal levels outside these specifications, also refer to the specification of the overload current I_{OV}.

Note: Operating Conditions apply.

Table 14 is valid under the following conditions:
$V_{DDP} \geq 4.5$ V; $V_{DDPtyp} = 5$ V; $V_{DDP} \leq 5.5$ V

Table 14 DC Characteristics for Upper Voltage Range

Parameter	Symbol	Values			Unit	Note / Test Condition
		Min.	Typ.	Max.		
Pin capacitance (digital inputs/outputs). To be doubled for double bond pins.[1)]	C_{IO} CC	–	–	10	pF	not subject to production test
Input Hysteresis[2)]	HYS CC	0.11 x V_{DDP}	–	–	V	R_S = 0 Ohm
Absolute input leakage current on pins of analog ports[3)]	$\|I_{OZ1}\|$ CC	–	10	200	nA	$V_{IN} > 0$ V; $V_{IN} < V_{DDP}$
Absolute input leakage current for all other pins. To be doubled for double bond pins.[3)1)4)]	$\|I_{OZ2}\|$ CC	–	0.2	5	µA	$T_J \leq 110$ °C; $V_{IN} < V_{DDP}$; $V_{IN} > V_{SS}$
		–	0.2	15	µA	$T_J \leq 150$ °C; $V_{IN} < V_{DDP}$; $V_{IN} > V_{SS}$
Pull Level Force Current[5)]	$\|I_{PLF}\|$ SR	250	–	–	µA	[6)]
Pull Level Keep Current[7)]	$\|I_{PLK}\|$ SR	–	–	30	µA	[6)]
Input high voltage (all except XTAL1)	V_{IH} SR	0.7 x V_{DDP}	–	V_{DDP} + 0.3	V	
Input low voltage (all except XTAL1)	V_{IL} SR	-0.3	–	0.3 x V_{DDP}	V	
Output High voltage[8)]	V_{OH} CC	V_{DDP} - 1.0	–	–	V	$I_{OH} \geq I_{OHmax}$
		V_{DDP} - 0.4	–	–	V	$I_{OH} \geq I_{OHnom}$[9)]

Table 15 DC Characteristics for Lower Voltage Range (cont'd)

Parameter	Symbol	Values			Unit	Note / Test Condition
		Min.	Typ.	Max.		
Output Low Voltage[8)]	V_{OL} CC	–	–	1.0	V	$I_{OL} \le I_{OLmax}$
		–	–	0.4	V	$I_{OL} \le I_{OLnom}$ [10)]

1) Because each double bond pin is connected to two pads (standard pad and high-speed pad), it has twice the normal value. For a list of affected pins refer to the pin definitions table in chapter 2.

2) Not subject to production test - verified by design/characterization. Hysteresis is implemented to avoid metastable states and switching due to internal ground bounce. It cannot suppress switching due to external system noise under all conditions.

3) If the input voltage exceeds the respective supply voltage due to ground bouncing ($V_{IN} < V_{SS}$) or supply ripple ($V_{IN} > V_{DDP}$), a certain amount of current may flow through the protection diodes. This current adds to the leakage current. An additional error current (I_{INJ}) will flow if an overload current flows through an adjacent pin. Please refer to the definition of the overload coupling factor K_{OV}.

4) The given values are worst-case values. In production test, this leakage current is only tested at 125 °C; other values are ensured by correlation. For derating, please refer to the following descriptions: Leakage derating depending on temperature (T_J = junction temperature [°C]): $I_{OZ} = 0.05 \times e^{(1.5 + 0.028 \times TJ>)}$ [µA]. For example, at a temperature of 95 °C the resulting leakage current is 3.2 µA. Leakage derating depending on voltage level (DV = V_{DDP} - V_{PIN} [V]): $I_{OZ} = I_{OZtempmax}$ - (1.6 x DV) (µA]. This voltage derating formula is an approximation which applies for maximum temperature.

5) Drive the indicated minimum current through this pin to change the default pin level driven by the enabled pull device: $V_{PIN} <= V_{IL}$ for a pullup; $V_{PIN} >= V_{IH}$ for a pulldown.

6) These values apply to the fixed pull-devices in dedicated pins and to the user-selectable pull-devices in general purpose IO pins.

7) Limit the current through this pin to the indicated value so that the enabled pull device can keep the default pin level: $V_{PIN} >= V_{IH}$ for a pullup; $V_{PIN} <= V_{IL}$ for a pulldown.

8) The maximum deliverable output current of a port driver depends on the selected output driver mode. This specification is not valid for outputs which are switched to open drain mode. In this case the respective output will float and the voltage is determined by the external circuit.

9) As a rule, with decreasing output current the output levels approach the respective supply level (VOL->VSS, VOH->VDDP). However, only the levels for nominal output currents are verified.

10) As a rule, with decreasing output current the output levels approach the respective supply level (V_{OL}->V_{SS}, V_{OH}->V_{DDP}). However, only the levels for nominal output currents are verified.

PLL frequency band selection

Different frequency bands can be selected for the VCO so that the operation of the PLL can be adjusted to a wide range of input and output frequencies:

Table 24 System PLL Parameters

Parameter	Symbol	Values			Unit	Note / Test Condition
		Min.	Typ.	Max.		
VCO output frequency (VCO controlled)	f_{VCO} CC	50	–	110	MHz	VCOSEL = 00_B
		100	–	160	MHz	VCOSEL = 01_B
VCO output frequency (VCO free-running)	f_{VCO} CC	10	–	40	MHz	VCOSEL = 00_B
		20	–	80	MHz	VCOSEL = 01_B

4.6.2.2 Wakeup Clock

When wakeup operation is selected (SYSCON0.CLKSEL = 00_B), the system clock is derived from the low-frequency wakeup clock source:

$f_{SYS} = f_{WU}$.

In this mode, a basic functionality can be maintained without requiring an external clock source and while minimizing the power consumption.

4.6.2.3 Selecting and Changing the Operating Frequency

When selecting a clock source and the clock generation method, the required parameters must be carefully written to the respective bit fields, to avoid unintended intermediate states.

Many applications change the frequency of the system clock (f_{SYS}) during operation in order to optimize system performance and power consumption. Changing the operating frequency also changes the switching currents, which influences the power supply.

To ensure proper operation of the on-chip EVRs while they generate the core voltage, the operating frequency shall only be changed in certain steps. This prevents overshoots and undershoots of the supply voltage.

To avoid the indicated problems, recommended sequences are provided which ensure the intended operation of the clock system interacting with the power system.
Please refer to the Programmer's Guide.

Table 26 is valid under the following conditions:
$V_{DDP} \geq 4.5$ V; $V_{DDPtyp} = 5$ V; $V_{DDP} \leq 5.5$ V; $C_L \geq 20$ pF; $C_L \leq 100$ pF;

Table 26 Standard Pad Parameters for Upper Voltage Range

Parameter	Symbol	Values			Unit	Note / Test Condition
		Min.	Typ.	Max.		
Maximum output driver current (absolute value)[1]	I_{Omax} CC	–	–	10	mA	Strong driver
		–	–	4.0	mA	Medium driver
		–	–	0.5	mA	Weak driver
Nominal output driver current (absolute value)	I_{Onom} CC	–	–	2.5	mA	Strong driver
		–	–	1.0	mA	Medium driver
		–	–	0.1	mA	Weak driver
Rise and Fall times (10% - 90%)	t_{RF} CC	–	–	4.2 + 0.14 x C_L	ns	Strong driver; Sharp edge
		–	–	11.6 + 0.22 x C_L	ns	Strong driver; Medium edge
		–	–	20.6 + 0.22 x C_L	ns	Strong driver; Slow edge
		–	–	23 + 0.6 x C_L	ns	Medium driver
		–	–	212 + 1.9 x C_L	ns	Weak driver

1) The total output current that may be drawn at a given time must be limited to protect the supply rails from damage. For any group of 16 neighboring output pins, the total output current in each direction (ΣI_{OL} and ΣI_{OH}) must remain below 50 mA.

Table 31 EBC External Bus Timing for Lower Voltage Range

Parameter	Symbol	Values			Unit	Note / Test Condition
		Min.	Typ.	Max.		
Output valid delay for $\overline{RD}$, $\overline{WR}$(L/$\overline{H}$)	t_{10} CC	–	11	20	ns	
Output valid delay for $\overline{BHE}$, ALE	t_{11} CC	–	10	21	ns	
Address output valid delay for A23 ... A0	t_{12} CC	–	11	22	ns	
Address output valid delay for AD15 ... AD0 (MUX mode)	t_{13} CC	–	10	22	ns	
Output valid delay for $\overline{CS}$	t_{14} CC	–	10	13	ns	
Data output valid delay for AD15 ... AD0 (write data, MUX mode)	t_{15} CC	–	10	22	ns	
Data output valid delay for D15 ... D0 (write data, DEMUX mode)	t_{16} CC	–	10	22	ns	
Output hold time for $\overline{RD}$, $\overline{WR}$(L/$\overline{H}$)	t_{20} CC	-2	8	10	ns	
Output hold time for $\overline{BHE}$, ALE	t_{21} CC	-2	8	10	ns	
Address output hold time for AD15 ... AD0	t_{23} CC	-3	8	10	ns	
Output hold time for $\overline{CS}$	t_{24} CC	-3	8	11	ns	
Data output hold time for D15 ... D0 and AD15 ... AD0	t_{25} CC	-3	8	10	ns	
Input setup time for READY, D15 ... D0, AD15 ... AD0	t_{30} SR	29	17	–	ns	
Input hold time READY, D15 ... D0, AD15 ... AD0[1)]	t_{31} SR	0	-9	–	ns	

1) Read data are latched with the same internal clock edge that triggers the address change and the rising edge of $\overline{RD}$. Address changes before the end of $\overline{RD}$ have no impact on (demultiplexed) read cycles. Read data can change after the rising edge of $\overline{RD}$.

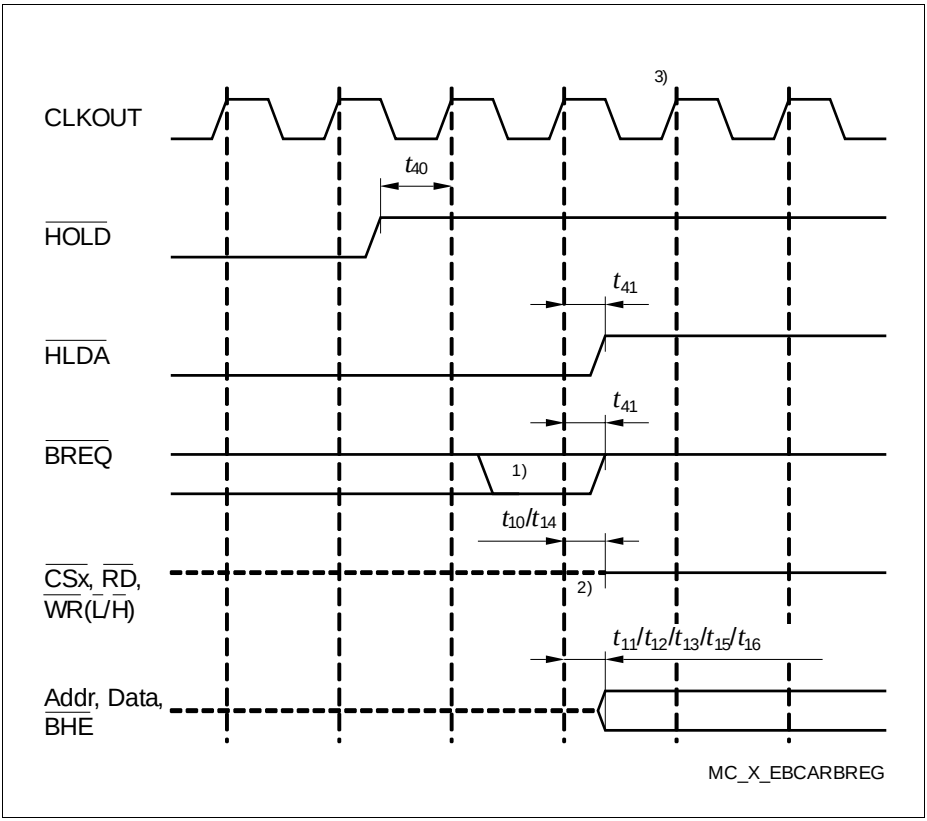

Figure 27 External Bus Arbitration, Regaining the Bus

Notes

1. *This is the last chance for BREQ to trigger the indicated regain sequence. Even if BREQ is activated earlier, the regain sequence is initiated by HOLD going high. Please note that HOLD may also be deactivated without the XC2785X requesting the bus.*
2. *The control outputs will be resistive high (pull-up) before being driven inactive (ALE will be low).*
3. *The next XC2785X-driven bus cycle may start here.*

4.6.7 Debug Interface Timing

The debugger can communicate with the XC2785X either via the 2-pin DAP interface or via the standard JTAG interface.

Debug via DAP

The following parameters are applicable for communication through the DAP debug interface.

Note: These parameters are not subject to production test but verified by design and/or characterization.

Note: Operating Conditions apply; C_L= 20 pF.

Table 38 DAP Interface Timing for Upper Voltage Range

Parameter	Symbol	Values			Unit	Note / Test Condition
		Min.	Typ.	Max.		
DAP0 clock period	t_{11} SR	25[1)]	–	–	ns	
DAP0 high time	t_{12} SR	8	–	–	ns	
DAP0 low time	t_{13} SR	8	–	–	ns	
DAP0 clock rise time	t_{14} SR	–	–	4	ns	
DAP0 clock fall time	t_{15} SR	–	–	4	ns	
DAP1 setup to DAP0 rising edge	t_{16} SR	6	–	–	ns	pad_type= standard
DAP1 hold after DAP0 rising edge	t_{17} SR	6	–	–	ns	pad_type= standard
DAP1 valid per DAP0 clock period[2)]	t_{19} CC	17	20	–	ns	pad_type= standard

1) The debug interface cannot operate faster than the overall system, therefore $t_{11} \geq t_{SYS}$.

2) The Host has to find a suitable sampling point by analyzing the sync telegram response.

Package Outlines

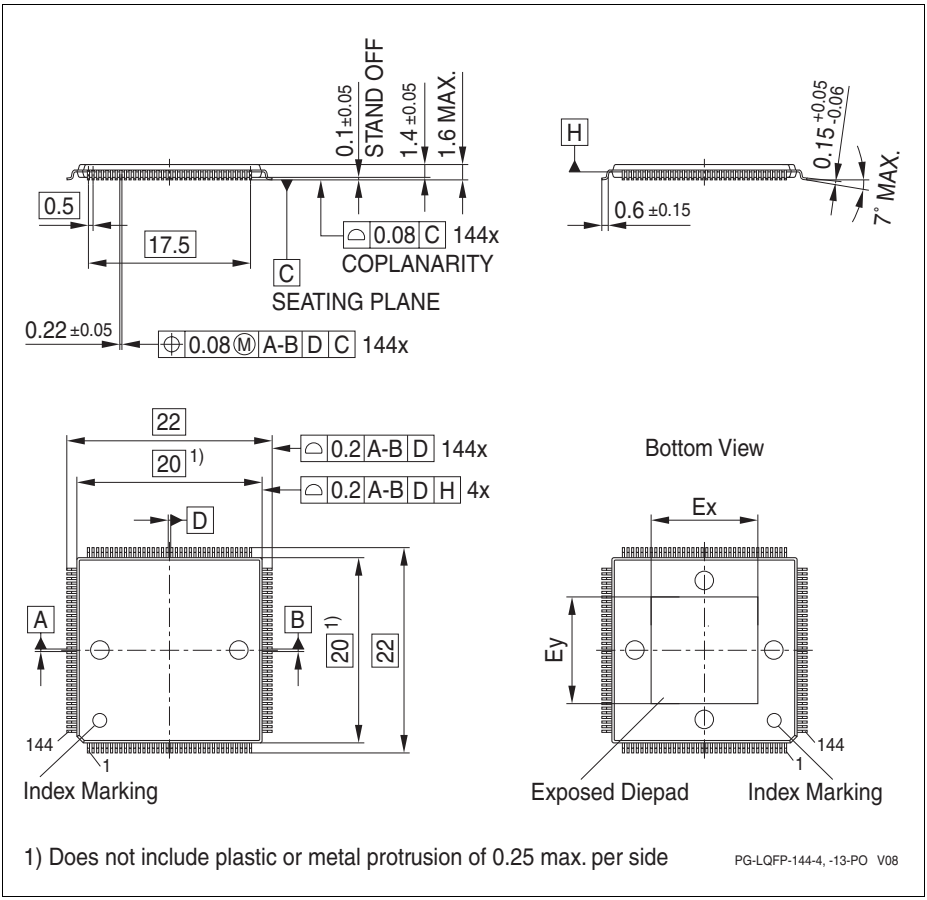

Figure 34 PG-LQFP-144-13 (Plastic Green Thin Quad Flat Package)

All dimensions in mm.

You can find complete information about Infineon packages, packing and marking in our Infineon Internet Page “Packages”: **http://www.infineon.com/packages**

5.2 Thermal Considerations

When operating the XC2785X in a system, the total heat generated in the chip must be dissipated to the ambient environment to prevent overheating and the resulting thermal damage.

The maximum heat that can be dissipated depends on the package and its integration into the target board. The “Thermal resistance $R_{\Theta JA}$” quantifies these parameters. The power dissipation must be limited so that the average junction temperature does not exceed 150 °C.

The difference between junction temperature and ambient temperature is determined by
$\Delta T = (P_{INT} + P_{IOSTAT} + P_{IODYN}) \times R_{\Theta JA}$

The internal power consumption is defined as
$P_{INT} = V_{DDP} \times I_{DDP}$ (switching current and leakage current).

The static external power consumption caused by the output drivers is defined as
$P_{IOSTAT} = \Sigma((V_{DDP}-V_{OH}) \times I_{OH}) + \Sigma(V_{OL} \times I_{OL})$

The dynamic external power consumption caused by the output drivers (P_{IODYN}) depends on the capacitive load connected to the respective pins and their switching frequencies.

If the total power dissipation for a given system configuration exceeds the defined limit, countermeasures must be taken to ensure proper system operation:

- Reduce V_{DDP}, if possible in the system
- Reduce the system frequency
- Reduce the number of output pins
- Reduce the load on active output drivers

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